PCN Number: 20211029000.2										PCN Date:		November 08, 2021
Title: Qualification of TI Chengdu as an additional Assembly a								nd T	Test sit	e for S	Select Devices	
Custom	er Conta	ict:	PCN A	Nanager		Dept:		Quality Serv	ices	5		
Proposed 1 st Ship Date: May 0				May 0	8,	2022 Estimated Sam Availabil			-	-		
Change	Change Type:											
	embly Site	е			Design				Wafer Bump Site			
Asse	embly Pro	ocess				Data Sheet				Wafer Bump Material		
	embly Ma	terials	s			Part number change				Wafer Bump Process		
Mec	hanical S	pecifi	cation	l	🛛 Test Site				Wafer Fab Site			
Packing/Shipping/Labeling					Test Process				Wafer Fab Materials			
										Wafe	r Fab I	Process
						PCN	Deta	ails				
Descrip	tion of C	hang	e:									

Texas Instruments Incorporated is announcing the qualification of TI Chengdu as an additional Assembly and Test site for the list of devices shown below. Construction differences between the 2 sites are as follows:

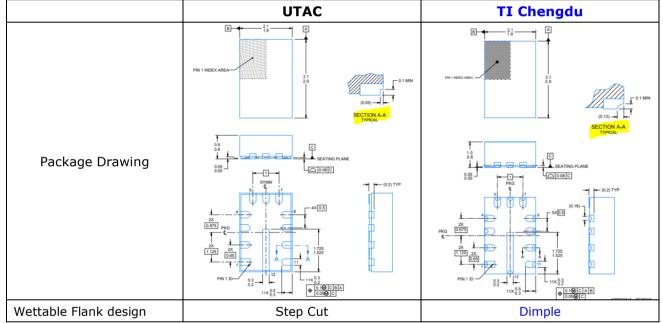
Assembly Site	Assembly Site Origin	Assembly Country Code	Assembly City
UTAC	NSE	THA	Bangkok
TI Chengdu	CDA	CHN	Chengdu

Material Differences:

	UTAC	TI Chengdu
Lead finish	Matte Sn	NiPdAu

Test coverage, insertions, conditions will remain consistent with current testing.

Package Outline Drawing Differences:



Reason for Change:

Supply continuity

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings or to the associated device component Test Reports.

RoHS	REACH	Green Status	IEC 62474
🛛 No Change	🛛 No Change	🛛 No Change	🛛 No Change

Changes to product identification resulting from this PCN:

Assembly Site								
UTAC Assembly Site Origin (22L) ASO: NSE								
CDAT Assembly Site Origin (22L) ASO: CDA								
Sample product shipping label (not actual product label) $G_3 = Matte Sn$ $G_4 = NiPdAu$ (1P) SN74LS07NSR (a) 2000 (b) 0336 (31T) LOT: 3959047MLA (W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0:USA (21L) AS0: MLA (23L) ACO: MYS								
Product Affected:								
LMR33620AQ5RNXRQ1	LMR33620BQRNXTQ1 LMR33620CQRNXRQ1 LMR33630BQRNXTQ1							
LMR33620AQ5RNXTQ1	LMR33620CQ3RNXRQ1	LMR33620CQRNXTQ1	LMR33630CQRNXRQ1					
LMR33620AQRNXRQ1	LMR33620CQ3RNXTQ1	LMR33630AQRNXRQ1	LMR33630CQRNXTQ1					
LMR33620AQRNXTQ1	LMR33620CQ5RNXRQ1	LMR33630AQRNXTQ1						
LMR33620BQRNXRQ1	LMR33620CQ5RNXTQ1	LMR33630BQRNXRQ1						

Qualification Report Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines) Approved 28-Sept-2020

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed Test Min SS/ Test Name / Qual Device: Qual Device: Qual Device: QBS Package Qual Spec Min SS/ Test Name / Duration Duration COAT Qual Device: Qual Device: QBS Package Qual Coder Coder CDAT UTL1 LMR33630CQRNXRQ1 UTL1: Cccelerated Environment Stress Tests Environment Stress Tests Environment Stress Tests Environment Stress Tests

iype	#	Spec	Qty	Lot	Condition	Duration	CDAT	UTL1	LMR33620CQRNXTQ1
Fest Group	A – A	ccelerated E	nvironr	nent Si	ress Tests				
PC	A1	JEDEC J-STD- 020 JESD22- A113	3	231	Automotive Preconditioning	Level 2- 260C	Pass	-	Pass
bHAST	A2	JEDEC JESD22-	3	77	Biased HAST, 110C/85%RH	264 Hours	3/231/0	-	-

		A101							
		JEDEC			Unbiased				
uHAST	A3	JESD22- A102	3	77	HAST, 110C/85%RH	264 Hours	3/231/0	-	-
		JEDEC			Biased				
THB		JESD22-	3	77	Temperature	1000	-		3/231/0
		A101	-		and Humidity,	Hours			
					85C/85%RH				
		JEDEC							
AC		JESD22-	3	77	Autoclave 121C	96 Hours	-		3/231/0
		A102							
		JEDEC							
		JESD22-			_				
тс	A4	A104	3	77	Temperature	500	3/231/0	-	3/231/0
		and			Cycle, -65/150C	Cycles			
		Appendix							
		3 JEDEC			Damas				
PTC	A5	JESD22-	1	45	Power Temperature	1000	1/44/1 (Note 1)		1/45/0
FIC	AJ	A105	'	43	Cycle	Cycles	1/44/1 (NOLE 1)	-	1/45/0
		JEDEC			High Temp.				
HTSL	A6	JESD22-	1	45	Storage Life,	1000	3/231/0	_	3/231/0
IIIOL	/10	A103		-10	150C	Hours	0/201/0		0/201/0
est Group	B - Ac	ccelerated L	ifetime	Simula					
oor oroup		JEDEC		Simula					
HTOL	B1	JESD22-	3	77	Life Test, 125C	1000	3/231/0	-	3/231/0
mol	5.	A108	Ŭ		210 1000, 1200	Hours	0/201/0		0/201/0
		AEC			Early Life				
ELFR	B2	Q100-	3	800	Failure Rate,	48 Hours	3/2400/0	_	3/2400/0
E EI IX	52	008	Ŭ	000	125C	10 Hourd	0/2 100/0		0/2 100/0
					NVM				
		AEC			Endurance,				
EDR	B3	Q100-	3	77	Data Retention,	10000	3/231/0	-	-
		005	-		and Operational	Cycles			
					Life				
est Group	C – Pa	ackage Asse	mbly Ir	ntegrity	Tests				
		AEC			Bond Shear				
WBS	C1	Q100-	1	30	Bond Shear (Cpk>1.67)	Wires	N/A	-	N/A
WBS	C1	Q100- 001	1	30	Bond Shear (Cpk>1.67)	Wires	N/A	-	N/A
WBS	C1	Q100- 001 MIL-	1	30	(Cpk>1.67)	Wires	N/A	-	N/A
WBS WBP	C1 C2	Q100- 001 MIL- STD883	1	30 30	(Cpk>1.67) Bond Pull	Wires	N/A N/A	-	N/A N/A
		Q100- 001 MIL- STD883 Method			(Cpk>1.67)			-	
		Q100- 001 MIL- STD883			(Cpk>1.67) Bond Pull (Cpk>1.67)			-	
		Q100- 001 MIL- STD883 Method			(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount			-	
		Q100- 001 MIL- STD883 Method 2011			(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability			-	
WBP	C2	Q100- 001 MIL- STD883 Method 2011 JEDEC	1	30	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead	Wires	N/A	-	N/A
WBP	C2	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102	1	30	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability	Wires	N/A	-	N/A
WBP	C2	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 JEDEC	1	30	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage	Wires	N/A	-	N/A
WBP SD	C2 C3	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 JEDEC JESD22-	1	30 15	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical	Wires 15	N/A 1/15/0	-	N/A Pass
WBP	C2	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 JEDEC JESD22- B100	1	30	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions	Wires	N/A	-	N/A
WBP SD	C2 C3	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 JESD22- B100 and	1	30 15	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical	Wires 15	N/A 1/15/0	-	N/A Pass
WBP SD	C2 C3	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 JEDEC JESD22- B100 and B108	1	30 15	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67)	Wires 15	N/A 1/15/0	-	N/A Pass
WBP SD PD	C2 C3 C4	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC	1	30 15 10	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball	Wires 15 30 units Solder	N/A 1/15/0 3/90/0	-	N/A Pass Pass
WBP SD	C2 C3	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100-	1	30 15	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear	Wires 15 30 units	N/A 1/15/0	- - - -	N/A Pass
WBP SD PD	C2 C3 C4	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010	1	30 15 10	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball	Wires 15 30 units Solder	N/A 1/15/0 3/90/0	- - -	N/A Pass Pass
WBP SD PD SBS	C2 C3 C4 C5	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC	1 1 3 3	30 15 10 50	(Cpk>1.67) Bond Pull (Cpk>1.67) Sulface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67)	Wires 15 30 units Solder Balls	N/A 1/15/0 3/90/0 N/A	-	N/A Pass Pass N/A
WBP SD PD	C2 C3 C4	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B100 and B108 AEC Q100- 010 JEDEC JESD22-	1	30 15 10	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear	Wires 15 30 units Solder	N/A 1/15/0 3/90/0	- - - -	N/A Pass Pass
WBP SD PD SBS LI	C2 C3 C4 C5 C6	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 and B108 AEC Q100- 010 JEDEC JESD22- B105	1 1 3 3 1	30 15 10 50 50	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity	Wires 15 30 units Solder Balls	N/A 1/15/0 3/90/0 N/A	-	N/A Pass Pass N/A
WBP SD PD SBS LI	C2 C3 C4 C5 C6	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B100 and B108 AEC Q100- 010 JEDEC JESD22-	1 1 3 3 1	30 15 10 50 50	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity	Wires 15 30 units Solder Balls	N/A 1/15/0 3/90/0 N/A N/A		N/A Pass Pass N/A N/A
WBP SD PD SBS LI	C2 C3 C4 C5 C6 D - Di	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B100 and B108 AEC Q100- 010 e Fabricatio	1 1 3 3 1	30 15 10 50 50	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity	Wires 15 30 units Solder Balls Leads	N/A 1/15/0 3/90/0 N/A N/A Completed Per Process	Completed Per Process Technology	N/A Pass Pass N/A N/A Completed Per
WBP SD PD SBS LI	C2 C3 C4 C5 C6	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B102 and B108 AEC Q100- 010 JEDEC JESD22- B105	1 1 3 3 1	30 15 10 50 50 bility T	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests	Wires 15 30 units Solder Balls	N/A 1/15/0 3/90/0 N/A N/A Completed Per Process Technology	Technology	N/A Pass Pass N/A N/A Completed Per Process Technology
WBP SD PD SBS LI	C2 C3 C4 C5 C6 D - Di	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B100 and B108 AEC Q100- 010 e Fabricatio	1 1 3 3 1	30 15 10 50 50 bility T	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n	Wires 15 30 units Solder Balls Leads	N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements	Technology Requirements	N/A Pass Pass N/A N/A Completed Per
WBP SD PD SBS LI est Group EM	C2 C3 C4 C5 C6 D – D1	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61	1 1 3 3 1	30 15 10 50 50 bility T	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n	Wires 15 30 units Solder Balls Leads	N/A N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process	Technology Requirements Completed Per Process	N/A Pass Pass N/A N/A N/A Completed Per Process Technology Requirements Completed Per
WBP SD PD SBS LI	C2 C3 C4 C5 C6 D - Di	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B100 and B108 AEC Q100- 010 e Fabricatio	1 1 3 3 1	30 15 10 50 50 bility T	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent	Wires 15 30 units Solder Balls Leads	N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology	Technology Requirements Completed Per Process Technology	N/A Pass Pass N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology
WBP SD PD SBS LI est Group EM	C2 C3 C4 C5 C6 D – D1	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61	1 1 3 3 1	30 15 10 50 bility T -	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent Dielectric	Wires 15 30 units Solder Balls Leads	N/A N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process	Technology Requirements Completed Per Process	N/A Pass Pass N/A N/A N/A Completed Per Process Technology Requirements Completed Per
WBP SD PD SBS LI est Group EM	C2 C3 C4 C5 C6 D – D1	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61 JESD61	1 1 3 3 1	30 15 10 50 bility T -	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent Dielectric Breakdown	Wires 15 30 units Solder Balls Leads	N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements	Technology Requirements Completed Per Process Technology Requirements	N/A Pass Pass Pass N/A N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements
WBP SD PD SBS LI EM EM	C2 C3 C4 C5 C6 D – Di D1 D2	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61 JESD61	1 1 3 3 1	30 15 10 50 bility T -	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent Dielectric Breakdown Hot Injection	Wires 15 30 units Solder Balls Leads 	N/A 1/15/0 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements	Technology Requirements Completed Per Process Technology Requirements Completed Per Process	N/A Pass Pass Pass N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements Completed Per
WBP SD PD SBS LI est Group EM	C2 C3 C4 C5 C6 D – D1	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61 JESD61	1 1 3 3 1	30 15 10 50 bility T -	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent Dielectric Breakdown	Wires 15 30 units Solder Balls Leads	N/A 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements Completed Per Process Technology Requirements Completed Per Process Technology	Technology Requirements Completed Per Process Technology Requirements Completed Per Process Technology	N/A Pass Pass Pass N/A N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology
WBP SD PD SBS LI EM EM	C2 C3 C4 C5 C6 D – Di D1 D2	Q100- 001 MIL- STD883 Method 2011 JEDEC JESD22- B100 and B108 AEC Q100- 010 JEDEC JESD22- B105 e Fabricatio JESD61 JESD61	1 1 3 3 1	30 15 10 50 bility T -	(Cpk>1.67) Bond Pull (Cpk>1.67) Surface Mount Solderability >95% Lead Coverage Physical Dimensions (Cpk>1.67) Solder Ball Shear (Cpk>1.67) Lead Integrity ests Electromigratio n Time Dependent Dielectric Breakdown Hot Injection	Wires 15 30 units Solder Balls Leads 	N/A 1/15/0 1/15/0 3/90/0 N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements	Technology Requirements Completed Per Process Technology Requirements Completed Per Process	N/A Pass Pass Pass N/A N/A N/A Completed Per Process Technology Requirements Completed Per Process Technology Requirements

						Instability		Requirements	Requirements	Requirements
	SM	D5	-	-	-	Stress Migration		Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
T	est Group	E – El	ectrical Veri	fication	n Tests					
	НВМ	E2	AEC Q100- 002	1	3	ESD - HBM	2500 V	1/3/0	1/3/0	1/3/0
	CDM	E3	AEC Q100- 011	1	3	ESD - CDM	750 V	1/3/0	1/3/0	1/3/0
	LU	E4	AEC Q100- 004	1	6	Latch-up	+/100mA, 150C	1/6/0	1/6/0	1/6/0
	ED	E5	AEC Q100- 005	3	30	Electrical Distribution	Cpk > 1.67	3/30/0	-	3/90/0

- QBS: Qual By Similarity

- Qual Device LMR33630CQRNXRQ1 is qualified at LEVEL2-260C

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I) : -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU Room : AC/uHAST

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Note 1: 1 fail was attributed to test issue and was discounted. FA available upon request.

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF

MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (<u>www.ti.com/legal/termsofsale.html</u>) or other applicable terms available either on <u>ti.com</u> or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.